

U.S. Patent Application Serial No. 09/778,245

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U.S. Patent Application Serial No. 09/778,245
Filed: February 6, 2001
Inventors: SHING LEE ET AL.
For: "SYSTEM FOR MEASURING POLARIMETRIC
SPECTRUM AND OTHER PROPERTIES OF A SAMPLE"
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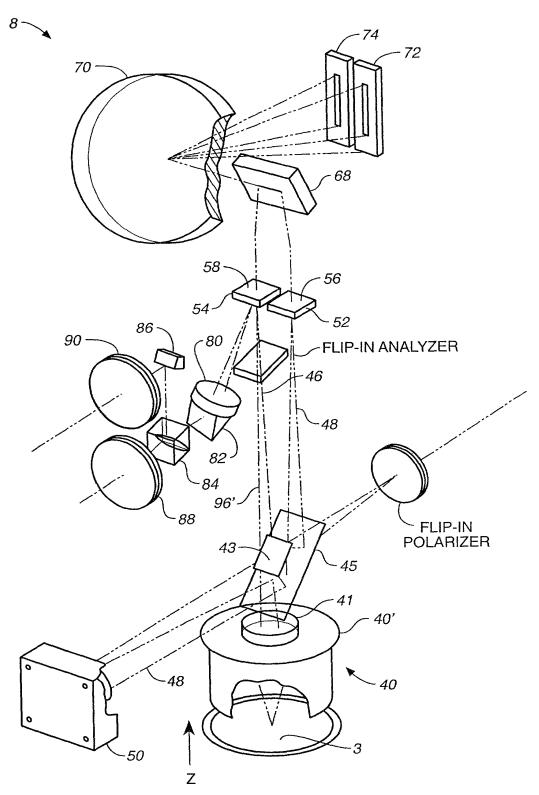


FIG._2

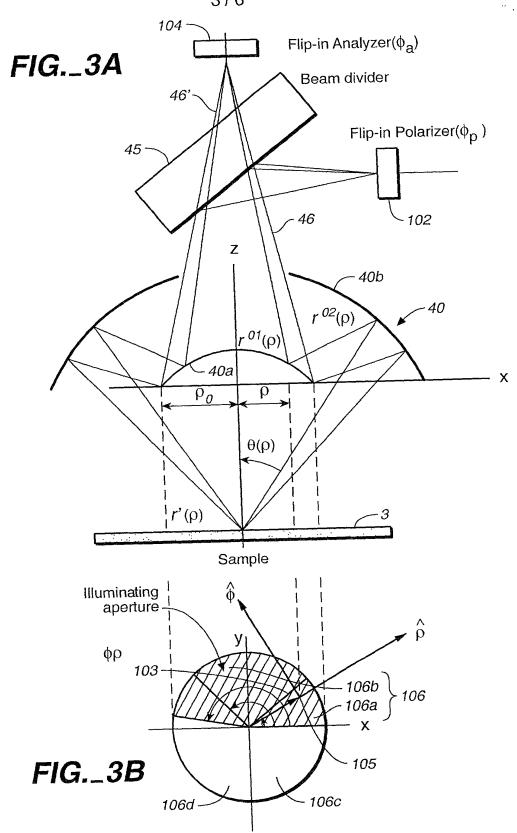
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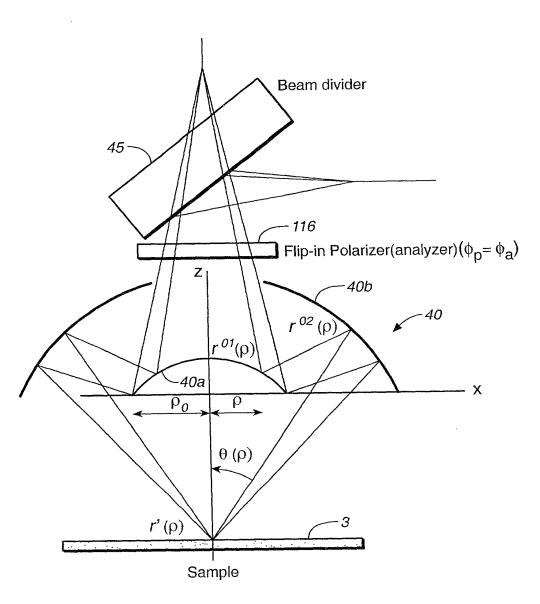
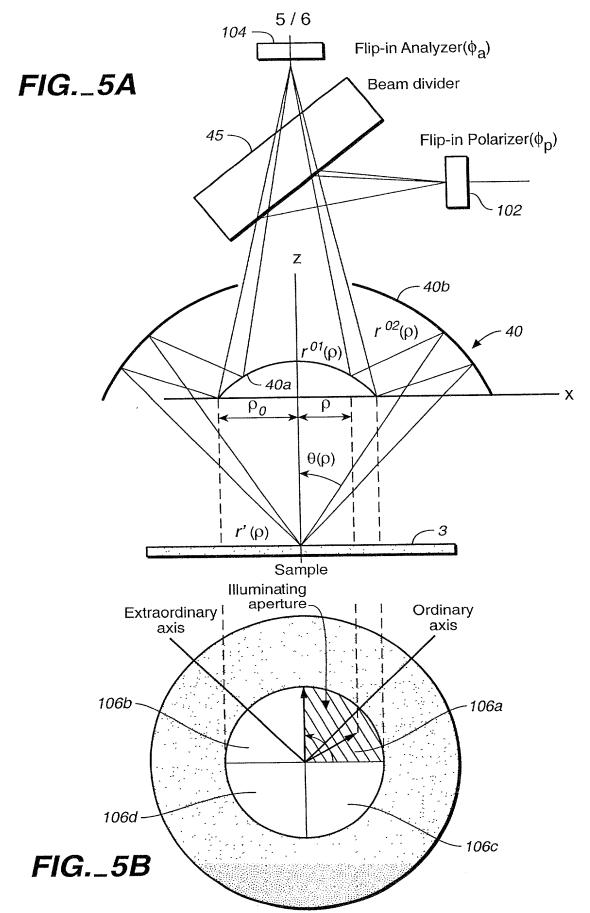


FIG._4

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